

P30192.A03



UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Yukio YANAGISAWA et al.

Group Art Unit : 1645

Appl. No. : 10/597,041 (National Stage
of PCT/JP2004/014930)

Examiner : Not Yet Assigned

Filed : July 7, 2006

Confirmation No. : 5114

For : PASSIVE TYPE EMISSION FLUX SAMPLER AND FLUX MEASURING
APPARATUS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop AMENDMENT
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby brings to the attention of the Examiner the following information.

The following documents were cited in an International Search Report issued with respect to International Patent Application No. PCT/JP2004/014930, of which the present application is the U.S. National Stage Application. Copies of the International Search Report (in Japanese and English) have been filed concurrently with the present application and should thus have already been brought to the attention of the Examiner.

- (1) Japanese Laid-Open Patent Publication No. HEI 11-118681, together with an English language computer-generated translation thereof;

- (2) Japanese Laid-Open Patent Publication No. 2003-247989, together with an English language Abstract of the same, and patent family members European Patent Publication No. EP 1 500 930 A1; and U.S. Patent Application Publication No. 2006/0018793 to HASHIBA et al., which was published on January 26, 2006;
- (3) Japanese Laid-Open Patent Publication No. HEI 7-229889, together with an English language Abstract of the same, and patent family member Canadian Patent Publication No. CA 2,129,463 A1; and
- (4) Japanese Laid-Open Patent Publication No. HEI 10-185775, together with an English language Abstract of the same, and patent family member U.S. Patent No. 6,139,801 to KAWACHI et al., which issued on October 31, 2000.

The relevance of the documents cited in the International Search Report, as ascertained with respect to the international claims by the International Examiner, is set forth in the International Search Report.

Applicants further submit the following document.

- (5) Japanese Laid-Open Patent Application Publication No. 2002-162322, together with an English language computer-generated translation thereof. Applicants note that the Japanese document is cited on page 3 of the specification of the above-captioned application.

Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. Patent and U.S. Patent Application Publication are not enclosed herewith. However, if any copy is needed, the

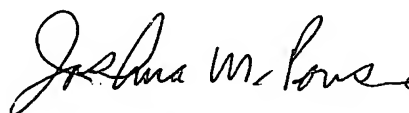
Examiner is respectfully requested to contact the undersigned.

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents, including the noted English language Abstracts and translations, are attached hereto, and all of the documents are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

Applicants note that an Office Action on the merits has not issued in the present application, and thus, no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,
Yukio YANAGISAWA et al.



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FORM PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket No.
P30192Application No.
10/597,041INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(Use several sheets if necessary)

Applicant
Yukio YANAGISAWA et al.Filing Date
July 7, 2006Group
1645

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6 1 3 9 8 0 1	10/31/00	KAWACHI et al.			
	2006	0 0 1 8 7 9 3	01/26/06	HASHIBA et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	11	- 1 1 8 6 8 1	04/30/99	JAPAN			X
	2003	- 2 4 7 9 8 9	09/05/03	JAPAN			
		1 5 0 0 9 3 0	01/26/05	E.P.O			
	7	- 2 2 9 8 8 9	08/29/95	JAPAN			
		2 1 2 9 4 6 3	02/13/95	CANADA			
	10	- 1 8 5 7 7 5	07/14/98	JAPAN			
	2002	- 1 6 2 3 2 2	06/07/02	JAPAN			X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	1	English language Abstract of JP 2003-247989.
	2	English language Abstract of JP 7-229889.
	3	English language Abstract of JP 10-185775.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.